



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L CEP 20.0001

CB Certificate No.: IECQ-L 2020.001

Schedule Number: IECQ-L CEP 20.0001-S

Rev No.: 5

Revision Date: 2024/10/23

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No	Products, Materials	Items, Parameter		Title, Code of specification, standard or method used
		No	Items, Parameter	
1	Integrated Circuits	1	Visual inspection (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		6	Biased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		7	Unbiased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		8	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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China Electronic Product Reliability and Environmental Testing Research Institute (CEPREI)

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		9	Power Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		10	High Temperature Storage Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		11	High Temperature Operating Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		12	Early Life Failure Rate	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		13	Wire Bond Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		14	Wire Bond Pull	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		15	Solderability	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		16	Physical Dimensions	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		17	Solder Ball Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		18	Pre- and Post-Stress Function/Parameter	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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		19	Electrostatic Discharge Human Body Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		20	Electrostatic Discharge Charged Device Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		21	Mechanical Shock	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		22	Variable Frequency Vibration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		23	Constant Acceleration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		24	Gross/Fine Leak	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		25	Package Drop	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		26	Die Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		27	Internal Water Vapor	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
2	Discrete Semiconductors	1	Visual inspection (Pre-conditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021

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		2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		6	Highly Accelerated Stress Test	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		7	High Humidity High Temp. Reverse Bias	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		8	Unbiased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		9	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021

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		10	Temperature Cycling Hot Test	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		11	Power Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		12	Physical Dimension	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		13	Wire Bond Pull Strength	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		14	Wire Bond Shear Strength	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		15	Die Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		16	Resistance to Solder Heat	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		17	Thermal Resistance	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021

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		18	Solderability	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		19	Constant Acceleration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		20	Vibration Variable Frequency	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		21	Mechanical Shock	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		22	Hermeticity	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		23	External Visual	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		24	Pre- and Post-Stress Electrical Test	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		25	Parametric Verification	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021

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		26	ESD HBM Characterization	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
		27	ESD CDM Characterization	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
3	Optoelectronic Semiconductors	1	Visual inspection (Pre- conditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		6	Wet High Temperature Operating Life1	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020

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		7	Wet High Temperature Operating Life ²	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		8	High Humidity High Temperature Reverse Bias	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		9	Power Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		10	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		11	High Temperature Operating Life 1	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		12	High Temperature Operating Life 2	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		13	Low Temperature Operating Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		14	Physical Dimension	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020

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		15	Wire Bond Pull	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		16	Wire Bond Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		17	Die Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		18	Resistance to Solder Heat	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		19	Solderability	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		20	External Visual	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		21	Electrostatic Discharge Human Body Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		22	Electrostatic Discharge Charged Device Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020

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		23	Constant Acceleration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		24	Vibration Variable Frequency	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		25	Mechanical Shock	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		26	Hermeticity	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
4	Multichip Modules (MCM)	1	Visual inspection (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS

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				AEC-Q104-REV-September 14, 2017
		5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		6	Biased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		7	Unbiased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		8	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		9	Power Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		10	High Temperature Storage Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		11	High Temperature Operating Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017

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		12	Early Life Failure Rate	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		13	Wire Bond Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		14	Wire Bond Pull	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		15	Solderability MCM External Leads	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		16	Physical Dimensions	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		17	Solder Ball Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		18	X-Ray	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		19	Acoustic Microscopy	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017

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		20	Pre- and Post-Stress Function/Parameter	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		21	Electrostatic Discharge Human Body Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		22	Electrostatic Discharge Charged Device Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		23	Mechanical Shock	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		24	Variable Frequency Vibration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		25	Constant Acceleration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		26	Gross/Fine Leak	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		27	Mechanical Shock Cavity Device Drop	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017

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		28	Die Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		29	Internal Water Vapor	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		30	Low Temperature Storage Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		31	MCM Drop Test	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		32	X-ray	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
		33	Acoustic Microscopy	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR MULTICHIP MODULES(MCM) IN AUTOMOTIVE APPLICATIONS AEC-Q104-REV-September 14, 2017
5	Passive components	1	Pre-and Post-Stress Electrical Test	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		2	High Temperature Exposure	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		3	Temperature Cycling	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14

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		4	Destructive Physical Analysis	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		5	Moisture Resistance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		6	Humidity Bias	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		7	High Temperature Operating Life	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		8	External Visual	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		9	Physical Dimensions	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		10	Terminal Strength	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		11	Resistance to Solvent	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		12	Mechanical Shock	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		13	Vibration	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		14	Resistance to Solder Heat	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		15	Thermal Shock	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		16	ESD	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14

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		17	Solderability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		18	Electrical Characterization	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		19	Flammability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		20	Board Flex	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		21	Terminal Strength (SMD)	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		22	Beam Load	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		23	Flame Retardance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		24	Rotation Life	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		25	Surge Voltage	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		26	Salt Spray	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		27	Shear Strength	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		28	Short Circuit Fault Current Durability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		29	Fault Current Durability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14

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		30	End-of-Life Mode Verification	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		31	Jump Start Endurance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		32	Load Dump Endurance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
6	Micro Electro-Mechanical System(MEMS) Pressure Sensor Devices	1	PrHTOL	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019
		2	PrLTOL	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019
		3	BPr	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019
		4	PPr	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019
		5	Visual inspection (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		6	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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		7	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		8	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		9	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		10	Biased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		11	Unbiased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		12	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		13	Power Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		14	High Temperature Storage Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		15	High Temperature Operating Life	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		16	Early Life Failure Rate	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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		17	Wire Bond Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		18	Wire Bond Pull	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		19	Solderability	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		20	Physical Dimensions	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		21	Solder Ball Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		22	Pre- and Post-Stress Function/Parameter	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		23	Electrostatic Discharge Human Body Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		24	Electrostatic Discharge Charged Device Model	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		25	Mechanical Shock	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		26	Variable Frequency Vibration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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		27	Constant Acceleration	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		28	Gross/Fine Leak	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		29	Package Drop	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		30	Die Shear	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		31	Internal Water Vapor	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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